



PTO FORM 1449

LIST OF PUBLICATIONS CITED BY APPLICANT	<u>Attorney Docket No.</u> 0120-0249.15	<u>Serial No.</u> 10/748,561
	<u>Applicants</u> Baranowski, et al.	
	<u>Filing Date</u> December 30, 2003	<u>Group</u> 1772

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
<i>MS</i>	2,194,958	03/26/40	Szegvari, et al.			12/08/39
	2,557,169	06/19/51	Benner, J.A.			03/18/48
	3,897,260	07/29/75	Yaginuma, et al.			02/25/74
	3,924,051	12/02/75	Wiggins, et al.			03/24/72
	4,151,924	05/01/79	Jameson			11/07/77
	4,198,369	04/15/80	Yoshikawa, et al.			01/15/79
	4,235,953	11/25/80	Kumins, et al.			03/16/78
	4,360,120	11/23/82	Samuel, et al.			06/26/81
	4,468,254	08/28/84	Yokoyama, et al.			04/14/83
	4,684,554	08/04/87	Ou-Yang			04/12/85
<i>MS</i>	5,018,632	05/28/91	Schmidt			06/29/90

FOREIGN PATENT DOCUMENTS

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<i>Mc</i>	5,060,818	10/29/91	Doi, et al.			02/11/91
	5,143,763	09/01/92	Yamada, et al.			07/11/91
	5,289,932	03/01/94	Dimeo, et al.			07/14/93
	5,296,129	03/22/94	Ikeda, et al.			11/27/91
	5,381,914	01/17/95	Koyama, et al.			05/07/92
	5,685,443	11/11/97	Taber, et al.			03/06/95
	5,772,076	06/30/98	Juk, et al.			07/26/96
	5,843,577	12/01/98	Ouhadi, et al.			03/22/95
	5,849,418	12/15/98	Hoenig, et al.			11/1/95
	5,855,836	01/05/99	Leyden, et al.			06/12/97
	5,955,163	09/21/99	White			10/28/96
	6,140,418	10/31/00	Yamashita et al.			05/21/98
<i>Mc</i>	US 2004/ 0191445 A1	09/30/04	Baranowski et al			03/27/03

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANS- LATION

OTHER PUBLICATIONS
(Including Author, Title, Date, Pertinent Pages)

EXAMINER

Richard C. Rye

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*EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP form. Draw a line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.